IEC60730BDSCL43RN

IEC60730B Library Release notes DSC v4.3

Rev. 0 — 30 September 2022   **Release notes**

1   Introduction

IEC60730B_DSC_4_3 is the actual version of the core self-test library for NXP devices with the 56800EX core. The library is certified by VDE/UL. It is dedicated for use in applications compliant with the Safety class B standard (specified by IEC 60730, IEC60335 and/or UL 60730, and UL 1998).

The library is released in a pre-compiled format, together with functional example projects and documentation describing the respective tests.

The library is created in close cooperation with the application team, who have vast experience in customer projects. The customer feedback is also taken into consideration.

2   What is new

When compared to the previous version of the library, the main changes are:

- The following devices were added to the DSC library: 56F82xxx, 56F84xxx, and 56F80xxx.

2.1   Description

The supported devices are the following:

- 56F80xxx
- 56F81xxx
- 56F82xxx
- 56F83xxx
- 56F84xxx

The supported/recommended IDEs are the following:

- Code Warrior 11.2

The tested components are the following:

- CPU registers
- Program counter
- Variable memory (RAM)
- Invariable memory (flash)
- Clock
- Digital I/O
- Analog I/O
- Stack
- Watchdog
- Touch Sensing Interface (TSI)

3 Optimizations, improvements, and changes

3.1 Library

The following devices were added to the DSC library: 56F82xxx, 56F84xxx, and 56F80xxx.

The 56F80xxx devices are only partially supported. For a full Class B test, it is necessary to add the FPU register test. It is currently out of scope of the NXP Library.

3.2 Documentation

The documentation for the library is a part of the SDK package and it is also available at www.nxp.com/iec60730.

The documentation of the IEC60730B library consists of:

- IEC60730B_Library_User_Guide_DSC_v4_3.pdf
- IEC60730B_Library_Release_Notes_DSC_v4_3.pdf

The example applications have their dedicated release notes and user guides.

3.3 Functional example projects

All information about the IEC60730B library is available at www.nxp.com/iec60730.

For functional example please contact NXP representative.

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